# International Rectifier

IRF2807S IRF2807L

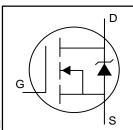
HEXFET® Power MOSFET

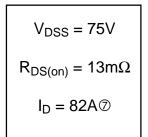
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

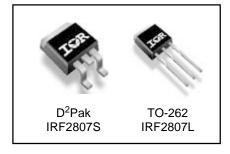
#### **Description**

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications. The D²Pak is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D²Pak is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

The through-hole version (IRF2807L) is available for low-profile applications.







#### **Absolute Maximum Ratings**

	<b>U</b>		
	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	82⑦	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	58	Α
I <sub>DM</sub>	Pulsed Drain Current ①	280	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	230	W
	Linear Derating Factor	1.5	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
I <sub>AR</sub>	Avalanche Current①	43	A
E <sub>AR</sub>	Repetitive Avalanche Energy①	23	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.9	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.65	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)**		40	0,11

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	75			V	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.074		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
Static Drain-to-Source On-Resistance			13	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 43A ④
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Forward Transconductance	38			S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 43A④
Drain-to-Source Leakage Current			25	μA	$V_{DS} = 75V$ , $V_{GS} = 0V$
			250		$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 150$ °C
Gate-to-Source Forward Leakage			100	<b>π</b> Λ	V <sub>GS</sub> = 20V
Gate-to-Source Reverse Leakage			-100	I IIA	V <sub>GS</sub> = -20V
Total Gate Charge			160		I <sub>D</sub> = 43A
Gate-to-Source Charge			29	nC	$V_{DS} = 60V$
Gate-to-Drain ("Miller") Charge			55		$V_{GS}$ = 10V, See Fig. 6 and 13
Turn-On Delay Time		13			$V_{DD} = 38V$
Rise Time		64		nc	$I_D = 43A$
Turn-Off Delay Time		49		115	$R_G = 2.5\Omega$
Fall Time		48			$V_{GS}$ = 10V, See Fig. 10 @
Internal Drain Inductance		4.5		nH	Between lead,
					6mm (0.25in.)
Internal Source Inductance		7.5			from package
					and center of die contact
Input Capacitance		3820			V <sub>GS</sub> = 0V
Output Capacitance		610			$V_{DS} = 25V$
Reverse Transfer Capacitance		130		pF	f = 1.0MHz, See Fig. 5
Single Pulse Avalanche Energy®		1280 ଓ	340⑥	mJ	I <sub>AS</sub> = 50A, L = 370μH
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance  Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time  Internal Drain Inductance  Input Capacitance Output Capacitance Reverse Transfer Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance  Breakdown Voltage  Cate Threshold Voltage  Cate Threshold Voltage  Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage  Gate-to-Source Reverse Leakage  Total Gate Charge Gate-to-Drain ("Miller") Charge  Turn-On Delay Time Rise Time  Turn-Off Delay Time Fall Time  Internal Drain Inductance  Input Capacitance  Output Capacitance  Reverse Transfer Capacitance	Drain-to-Source Breakdown Voltage         75         —           Breakdown Voltage Temp. Coefficient         —         0.074           Static Drain-to-Source On-Resistance         —         —           Gate Threshold Voltage         2.0         —           Forward Transconductance         38         —           Drain-to-Source Leakage Current         —         —           Gate-to-Source Forward Leakage         —         —           Gate-to-Source Reverse Leakage         —         —           Total Gate Charge         —         —           Gate-to-Source Charge         —         —           Gate-to-Drain ("Miller") Charge         —         —           Turn-On Delay Time         —         13           Rise Time         —         49           Fall Time         —         48           Internal Drain Inductance         —         4.5           Internal Source Inductance         —         3820           Output Capacitance         —         610           Reverse Transfer Capacitance         —         130	Drain-to-Source Breakdown Voltage         75         —         —           Breakdown Voltage Temp. Coefficient         —         0.074         —           Static Drain-to-Source On-Resistance         —         —         13           Gate Threshold Voltage         2.0         —         4.0           Forward Transconductance         38         —         —           Drain-to-Source Leakage Current         —         25         —         25           Gate-to-Source Leakage Current         —         —         25         —         —         25           Gate-to-Source Forward Leakage         —         —         —         100           Gate-to-Source Reverse Leakage         —         —         100           Gate-to-Source Charge         —         —         29           Gate-to-Source Charge         —         —         29           Gate-to-Drain ("Miller") Charge         —         —         55           Turn-On Delay Time         —         13         —           Rise Time         —         44         —           Fall Time         —         48         —           Internal Drain Inductance         —         7.5         —	Drain-to-Source Breakdown Voltage         75         —         V           Breakdown Voltage Temp. Coefficient         —         0.074         —         V/°C           Static Drain-to-Source On-Resistance         —         —         13         mΩ           Gate Threshold Voltage         2.0         —         4.0         V           Forward Transconductance         38         —         —         S           Drain-to-Source Leakage Current         —         25         μA           Gate-to-Source Forward Leakage         —         —         100         nA           Gate-to-Source Reverse Leakage         —         —         160         nA           Gate-to-Source Charge         —         —         160         nC           Gate-to-Drain ("Miller") Charge         —         —         55           Turn-On Delay Time         —         13         —           Rise Time         —         49         —           Fall Time         —         48         —           Internal Drain Inductance         —         7.5         —           Input Capacitance         —         3820         —           Output Capacitance         —         610         <

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			000		MOSFET symbol
	(Body Diode)		82	82⑦	A	showing the
I <sub>SM</sub>	Pulsed Source Current		280	200	] ^`	integral reverse
	(Body Diode)①			200		p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$ , $I_S = 43A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		100	150	ns	$T_J = 25$ °C, $I_F = 43$ A
Q <sub>rr</sub>	Reverse Recovery Charge		410	610	nC	di/dt = 100A/µs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\begin{tabular}{ll} \hline @ Starting $T_J = 25^{\circ}C$, $L = 370\mu$H \\ $R_G = 25\Omega$, $I_{AS} = 43A$, $V_{GS} = 10V$ (See Figure 12) \\ \hline \end{tabular}$
- $\label{eq:loss} \begin{array}{l} \text{ } 3 \text{ } I_{SD} \leq 43A, \text{ } di/dt \leq 300A/\mu s, \text{ } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}\text{C} \end{array}$
- 4 Pulse width  $\leq$  400 $\mu$ s; duty cycle  $\leq$  2%.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- © This is a calculated value limited to  $T_J = 175$ °C.
- Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- \*\*When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994

# International TOR Rectifier

### IRF2807S/IRF2807L

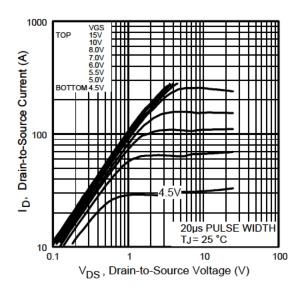


Fig 1. Typical Output Characteristics

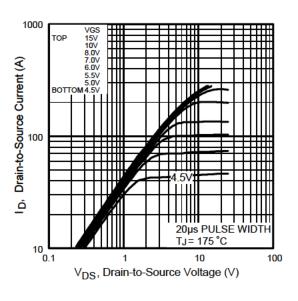


Fig 2. Typical Output Characteristics

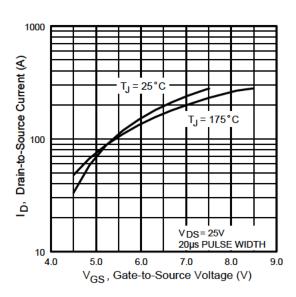


Fig 3. Typical Transfer Characteristics

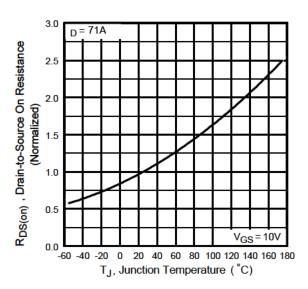


Fig 4. Normalized On-Resistance Vs. Temperature

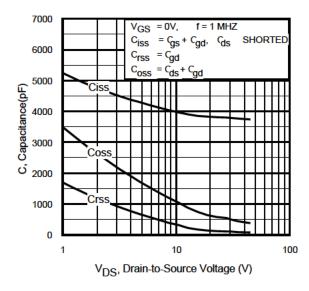
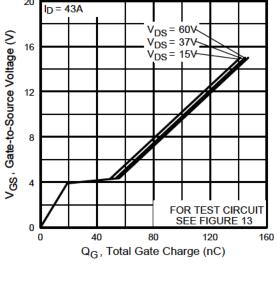


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

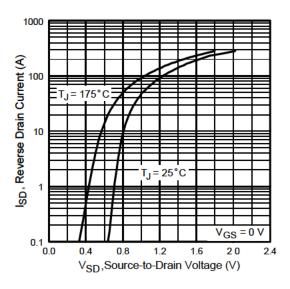


Fig 7. Typical Source-Drain Diode Forward Voltage

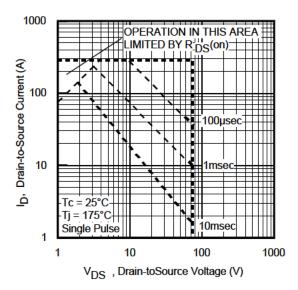


Fig 8. Maximum Safe Operating Area

# International TOR Rectifier

### IRF2807S/IRF2807L

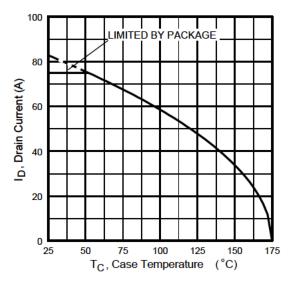


Fig 9. Maximum Drain Current Vs. Case Temperature

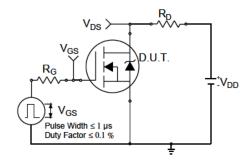


Fig 10a. Switching Time Test Circuit

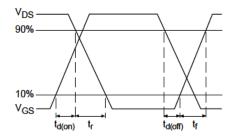


Fig 10b. Switching Time Waveforms

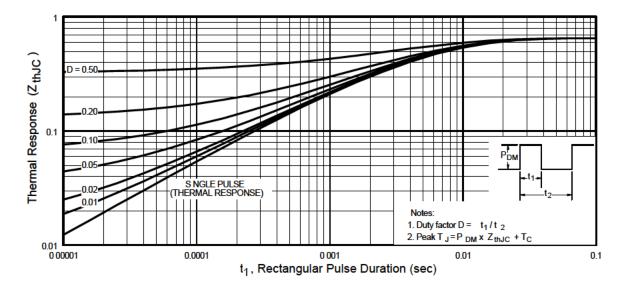


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

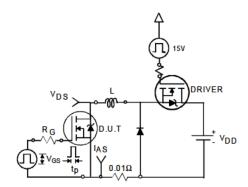


Fig 12a. Unclamped Inductive Test Circuit

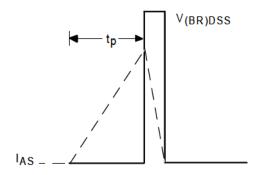


Fig 12b. Unclamped Inductive Waveforms

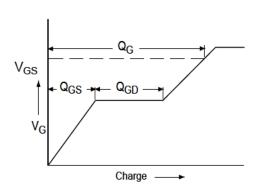


Fig 13a. Basic Gate Charge Waveform

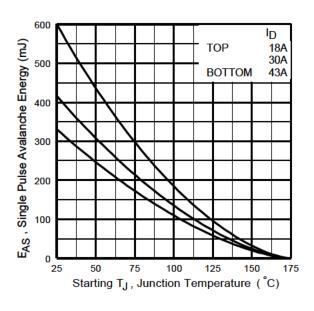


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

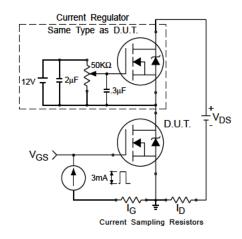
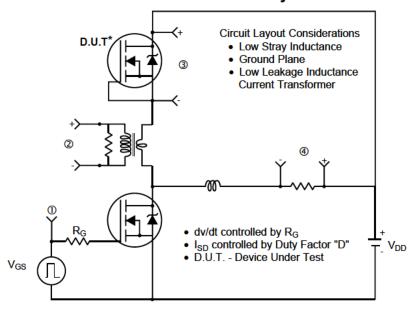
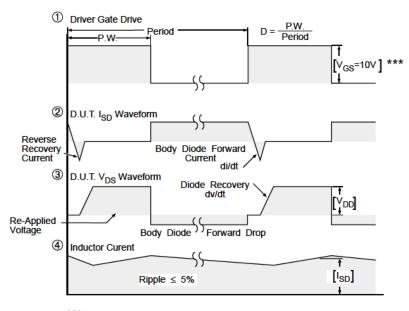


Fig 13b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit



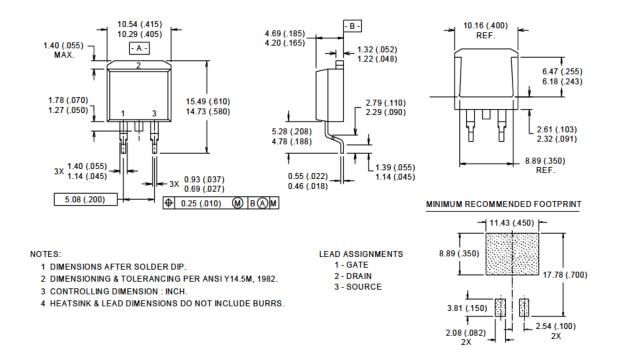
\* Reverse Polarity of D.U.T for P-Channel



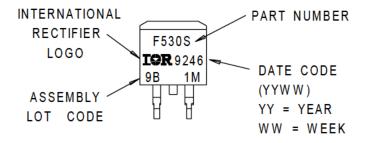
\*\*\*  $V_{GS}$  = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

#### D<sup>2</sup>Pak Package Outline



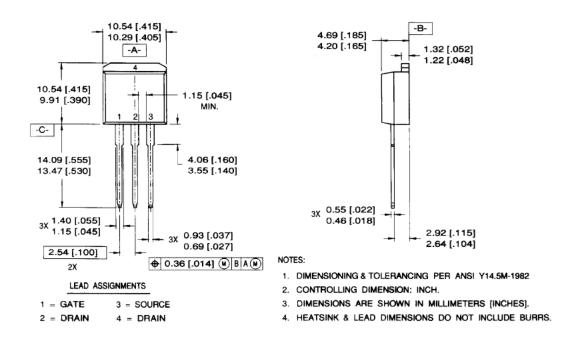
#### D<sup>2</sup>Pak Part Marking Information



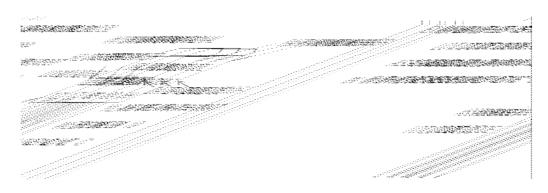
## International TOR Rectifier

### IRF2807S/IRF2807L

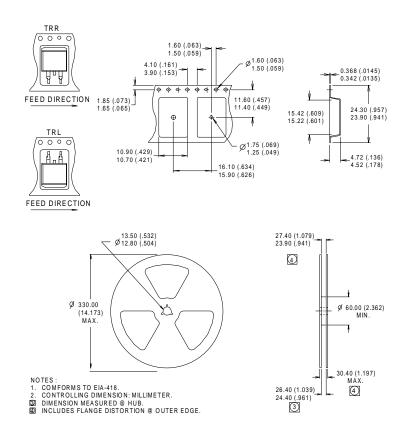
#### TO-262 Package Outline



#### TO-262 Part Marking Information



### D<sup>2</sup>Pak Tape & Reel Information



Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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